	Type	L #	Hits	Search Text	DBs
1	BRS	L1	0	allen near ernest.ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
2	BRS	L2	0	castanrda near david.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
3	BRS	L4	8	castaneda near david.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
4	BRS	L3	55	allen near ernest.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Type	L #	Hits	Search Text	DBs
5	BRS	L5	0	looi near miaw.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
6	BRS	L6	6106	(wafer or substrate) near25 (test) near25 (dies or chips)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
7	BRS	L7	25	(wafer or substrate) near25 (test) near25 (dies or chips) near25 (probe near tips)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
8	BRS	L8	4	(wafer or substrate) near25 (test) near25 (street or scribe$1) near25 (probe near tips)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Type	L #	Hits	Search Text	DBs
9	BRS	L9	5	(wafer or substrate) near25 (street or scribe$1) near25 (probe near tips)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
10	BRS	L10	165	(wafer or substrate) near25 (street or scribe$1) near25 (probe)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
11	BRS	L11	53	(wafer or substrate) near25 (street or scribe$1) near25 (probe) near10 (pad$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
12	BRS	L12	1	(wafer or substrate) near25 (street or scribe$1) near25 (probe) near10 (pad$1) near25 (cell or identif$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Type	L #	Hits	Search Text	DBs
13	BRS	L13	5	(wafer or substrate) near25 (street or scribe$1) near25 (probe) near25 (cell or identif$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
14	BRS	L14	3	"6714031".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
15	BRS	L15	1	(identification near nuber)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
16	BRS	L16	59113	(identification near number)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Type	L #	Hits	Search Text	DBs
17	BRS	L17	12	(identification near number) near15 (wafer oe substrate) near15 (street$1 ot scribe$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
18	BRS	L18	81	(identification) near15 (wafer oe substrate) near15 (street$1 ot scribe$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
19	BRS	L19	0	(pad$1) near15 (identification) near15 (wafer oe substrate) near15 (street$1 ot scribe$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
20	BRS	L20	16	(pad$1) near15 (cell) near15 (wafer oe substrate) near15 (street$1 ot scribe$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Type	L #	Hits	Search Text	DBs
21	BRS	L21	0	(metal$3 near pad$1) near15 (cell) near15 (wafer oe substrate) near15 (street$1 ot scribe$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
22	BRS	L22	6	(metal$3 near pad$1) near15 (wafer oe substrate) near15 (street$1 ot scribe$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
23	BRS	L23	144	(pad$1) near15 (wafer oe substrate) near15 (street$1 ot scribe$1) and (identification or cell)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
24	BRS	L24	139	(pad$1) near15 (wafer or substrate) near15 (street$1 ot scribe$1) and (identification or cell)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Type	L #	Hits	Search Text	DBs
25	BRS	L25	1	(pad$1) near15 (wafer or substrate) near15 (street$1 ot scribe$1) and (identification near cell)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
26	BRS	L26	44853	(second near5 pad$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
27	BRS	L27	3	(second near5 pad$1) near25 (in) near10 (scribe or street)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
28	BRS	L28	40	(pad$1) near5 (in) near10 (scribe or street)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Type	L #	Hits	Search Text	DBs
29	BRS	L29	0	((pad$1) near15 (in) near30 (scribe or street)) near25 (cell or identif$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
30	BRS	L30	54	((pad$1) near15 (in) near30 (scribe or street)) and (cell or identif$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
31	BRS	L31	3	((pad$1) near15 (in) near30 (scribe or street)) and (cell near5 identif$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
32	BRS	L32	5	((pad$1) near15 (in) near30 (scribe or street)) and (cell or identif$4) near25 (metal$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Type	L #	Hits	Search Text	DBs
33	BRS	L33	5	(((pad$1) near15 (in) near30 (scribe or street)) near25 (current or volage)) and (cell or identif$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
34	BRS	L34	31	(((pad$1) near15 (in) near30 (scribe or street)) and (current or volage)) and (cell or identif$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
35	BRS	L35	14	(cell near identification) near15 (chips or dies)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
36	BRS	L36	34533	(cell or identification) near15 (chips or dies)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Type	L #	Hits	Search Text	DBs
37	BRS	L37	3142	((cell or identif$4) near15 (chips or dies)) near25 (output)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
38	BRS	L38	2976	((cell or identif$4) near15 (chips or dies)) near15 (output)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
39	BRS	L40	6	((cell or identif$4) near15 (chips or dies)) near15 (output) near15 (test) near15 (contact)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
40	BRS	L41	22	((cell or identif$4) near15 (chips or dies)) near15 (output) near15 (test) near15 (current or voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Type	L #	Hits	Search Text	DBs
41	BRS	L39	198	((cell or identif$4) near15 (chips or dies)) near15 (output) near15 (test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	U	1	Document ID	Title
1			US 20020095633 A1	Electronic component, a test configuration and a method for testing connections of electronic components on a printed circuit board
2			US 20020049927 A1	SEMICONDUCTOR INTEGRATED CIRCUIT
3			US 6487682 B2	Semiconductor integrated circuit
4			US 4768195 A	Chip tester
5			US 4183460 A	In-situ test and diagnostic circuitry and method for CML chips
6			RU 2116687 C	Device for testing electrostatic discharges